

OC10 Rec'd PCT/PTO 2 1 MAR 2002

Docket No.: 2134-022

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

35
07/9
1-1703

In re Application of :
Michael WOLLITZER :
Serial No. n/a : Group Art Unit:
Filed: Herewith : Examiner:
For: MEASURING PROBE FOR MEASURING HIGH FREQUENCIES AND METHOD
OF PRODUCING THE SAME

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents
Washington, D. C. 20231

Sir:

Prior to examination on the merits, please amend the
referenced application as follows:

IN THE CLAIMS:

Please amend claims 1-6 as follows:

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1. (amended) Measuring probe for measuring high frequencies,
comprising a contact end for contacting planar structures and a co-
axial cable end for connection to a co-axial cable; a co-planar
conductor structure having at least two conductors arranged between
the contact end and the co-axial cable end; a dielectric for
mounting the co-planar conductor structure, the dielectric being
arranged on the co-planar conductor structure; the dielectric being
arranged on at least one side of the co-planar conductor structure
in a central section between, and spaced, in the direction of
propagation, from the co-axial cable end and the contact end, each